## Notice of References Cited Application/Control No. 10/751,716 Examiner Steven S. Paik Applicant(s)/Patent Under Reexamination DE MOL VAN OTTERLOO, MAAR Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0004073	01-2004	Clothier, Brian L.	219/620
	В	US-6,512,894 B2	01-2003	Takemoto et al.	399/12
	С	US-6,233,409 B1	05-2001	Haines et al.	399/10
	D	US-6,529,692 B1	03-2003	Haines et al.	399/27
	Е	US-			
	F	US			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			=		
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	×	$\cdot$ .						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.